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PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Rodney Smedt et al.

Application No.: 10/714,460

Filed: November 14, 2003

For: MEASUREMENT OF OVERLAY USING
DIFFRACTION GRATINGS WHEN
OVERLAY EXCEEDS THE GRATING
PERIOD

Confirmation No.: 2490

Group Art Unit: 2812

Examiner: Unknown

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Box 1450 Alexandria, VA 22313-1450 on June 14, 2004.
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